

Electronic Patent Application Fee Transmittal

Application Number:	10723278			
Filing Date:	24-Nov-2003			
Title of Invention:	Method for testing semiconductor memory device and test circuit for semiconductor memory device			
First Named Inventor:	Munehiro Ito			
Filer:	Max Moskowitz/Cheryl Godfrey			
Attorney Docket Number:	P/29-1642			
Filed as Large Entity				
Utility Filing Fees				
Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				
Extension - 3 months with \$0 paid	1253	1	1020	1020

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Miscellaneous:				
Request for continued examination	1801	1	790	790
Total in USD (\$)				1810